

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
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Enter keywords or phrases, select fields, and select operators

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AND	<input type="text"/>	in	All Fields
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**OPTION 2**

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<div>measure<near/3> code-sequence and parameter <near/3> load and code- sequence<near/3> sent and unit<near/3> time</div> <div><input type="text"/></div>	
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IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

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